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0504-1048

PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Hao-Wen CHIU et al.

Confirmation No. 5884

Serial No. 10/015,587

Group 1731

Filed December 17, 2001

Examiner Unassigned

MOLD AND A METHOD OF HOT-FORMING
A THERMOPLASTIC LENS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying documents, copies of which are attached to this statement, are made of record on the enclosed sheet.

A concise explanation of the relevance of these items is that these references were cited by the International Search Report in the corresponding international Application No. PCT/FR 02/04386, filed December 17, 2002.

Under the provisions of 37 CFR 1.97(e), the undersigned hereby certifies that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign Patent Office in a

CHIU et al. S.N. 10/015,587

counterpart foreign application not more than three months prior to the filing of this Statement.

Respectfully submitted,

YOUNG & THOMPSON

By

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August 20, 2003

INFORMATION DISCLOSURE IN AN APPLICATION

(Use several sheets if necessary.)

Attorney Docket No.:
0504-1048

Application No.:

Applicant:
CHIU et al.

Filing Date:

Group Art Unit:
1731

~~U.S. GOVERNMENT DOCUMENTS~~

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FOREIGN PATENT DOCUMENTS

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER:

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

* Abstract provided for the Examiner's convenience